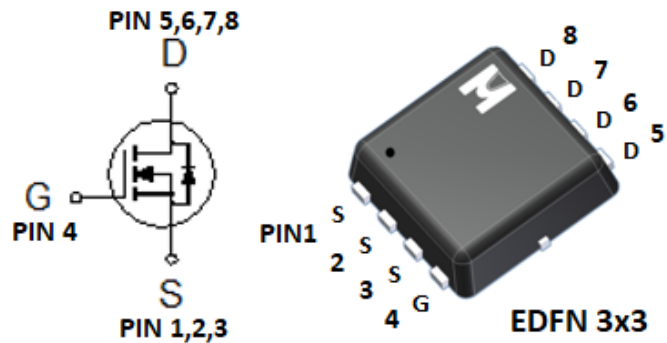


Single N-Channel Logic Level Enhancement Mode Field Effect Transistor

▪ Product Summary:

	N-CH
BV_{DSS}	30V
$R_{DS(on) (MAX.)}@V_{GS}=10V$	7.0m Ω
$R_{DS(on) (MAX.)}@V_{GS}=4.5V$	9.0m Ω
$I_D @T_C=25^{\circ}C$	59A
$I_D @T_A=25^{\circ}C$	13A

▪ Pin Description:



Single N Channel MOSFET

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant



▪ ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ¹	$T_C = 25^{\circ}C$	I_D	59	A
	$T_C = 100^{\circ}C$		39	
	$T_A = 25^{\circ}C$		13	
	$T_A = 70^{\circ}C$		10	
Pulsed Drain Current ¹		I_{DM}	107	mJ
Avalanche Current ^{1,4}		I_{AS}	33	
Avalanche Energy ^{1,4}		E_{AS}	54	
Repetitive Avalanche Energy ^{2,4}		E_{AR}	27	W
Power Dissipation ¹	$T_C = 25^{\circ}C$	P_D	46.3	
	$T_C = 100^{\circ}C$		18.5	W
Power Dissipation ¹	$T_A = 25^{\circ}C$	P_D	2.2	
	$T_A = 70^{\circ}C$		1.4	°C
Operating Junction & Storage Temperature Range		$T_{j, T_{stg}}$	-55 to 150	°C

▪ 100% UIS testing in condition of $V_D=25V$, $L=0.1mH$, $V_G=10V$, $I_L=20A$, $R_G=25\Omega$, Rated $V_{DS}=30V$ N-CH

▪ THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case		$R_{\theta JC}$		2.7	°C / W
Junction-to-Ambient ³	$t \leq 10s$	$R_{\theta JA}$		25	
	Steady-State	$R_{\theta JA}$		58	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

³The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}C$.

⁴Guarantee by Engineering test

▪ ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage ⁴	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	30			V
Gate Threshold Voltage ⁴	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	1.2	1.7	2.5	
Gate-Body Leakage ⁴	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current ⁴	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V			1	μA
		V _{DS} =30V, V _{GS} =0V, T _J = 125 °C			25	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 10V, V _{GS} = 10V	59			A
Drain-Source On-State Resistance ^{1,4}	R _{DS(ON)}	V _{GS} = 10V, I _D = 14A		5.3	7.0	mΩ
		V _{GS} = 4.5V, I _D = 10A		7.5	9.0	
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 20A		63		S
DYNAMIC						
Input Capacitance ⁵	C _{iss}	V _{GS} = 0V, V _{DS} = 15V, f = 1MHz		1020		pF
Output Capacitance ⁵	C _{oss}			160		
Reverse Transfer Capacitance ⁵	C _{rss}			110		
Gate Resistance ^{4,5}	R _g	f = 1MHz		2.0		Ω
Total Gate Charge ^{1,2,5}	Q _g (V _{GS} =10V)	V _{DS} = 15V, V _{GS} = 10V, I _D = 14A		21		nC
	Q _g (V _{GS} =4.5V)			9.6		
Gate-Source Charge ^{1,2,5}	Q _{gs}			4.0		
Gate-Drain Charge ^{1,2,5}	Q _{gd}			3.6		
Turn-On Delay Time ^{1,2,5}	t _{d(on)}	V _{DS} = 15V, V _{GS} = 10V, I _D = 5A , R _g = 3Ω		5.4		nS
Rise Time ^{1,2,5}	t _r			7.2		
Turn-Off Delay Time ^{1,2,5}	t _{d(off)}			20		
Fall Time ^{1,2,5}	t _f			9.7		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I _S				39	A
Pulsed Current ³	I _{SM}				107	
Forward Voltage ^{1,4}	V _{SD}	I _F = I _S =14A, V _{GS} = 0V			1.2	V
Reverse Recovery Time ⁵	t _{rr}	I _F = 14A, dI _F /dt = 100A / μS		7.6		nS
Peak Reverse Recovery Current ⁵	I _{RM(REC)}			0.4		A
Reverse Recovery Charge ⁵	Q _{rr}			2.5		nC

¹ Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

² Independent of operating temperature.

³ Pulse width limited by maximum junction temperature.

⁴ Guarantee by FT test Item

⁵ Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



•TYPICAL CHARACTERISTICS

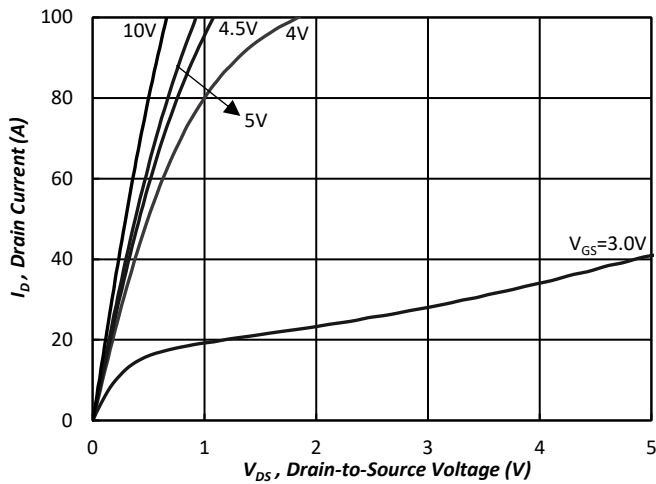


Fig.1 Typical Output Characteristics

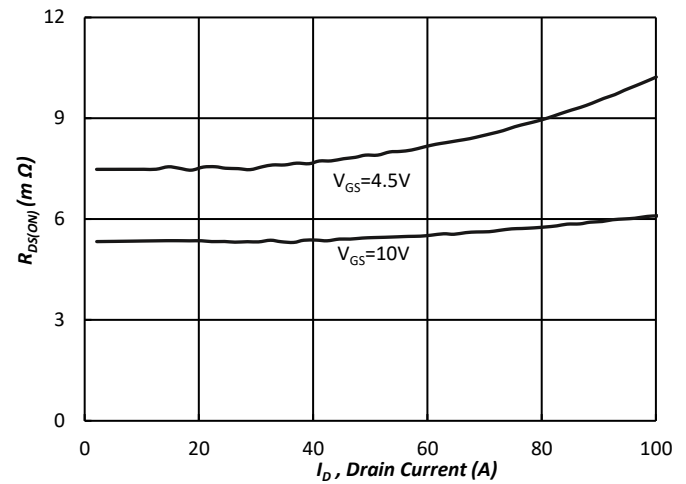


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

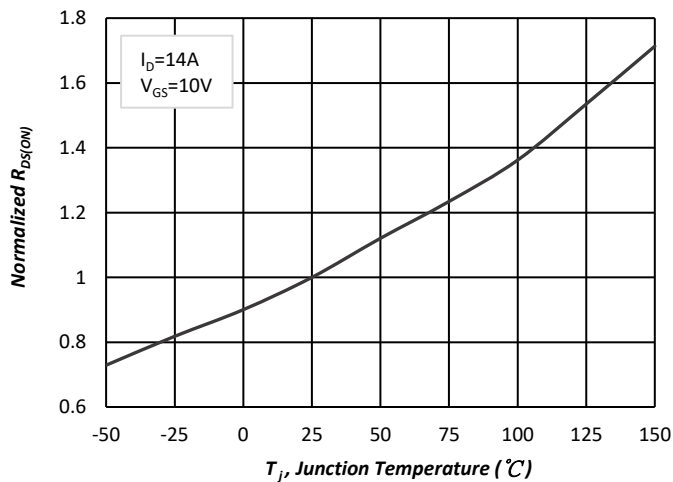


Fig.3 Normalized On-Resistance v.s. Junction Temperature

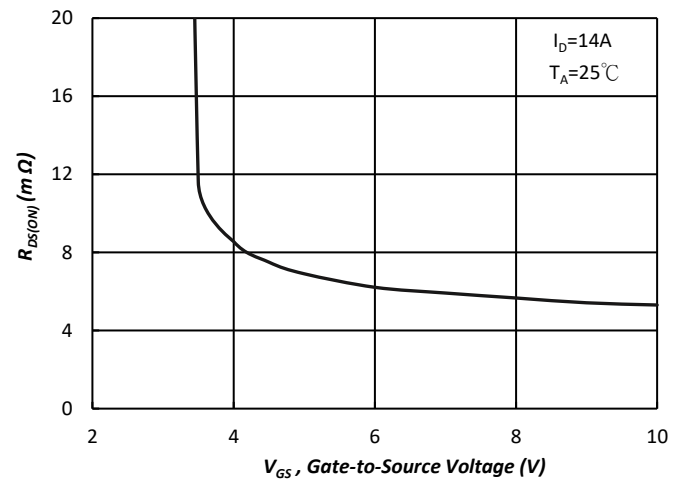


Fig.4 On-Resistance v.s. Gate Voltage

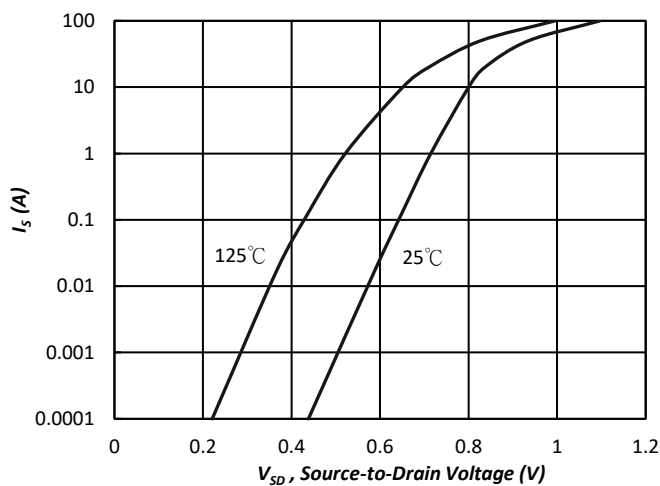


Fig.5 Forward Characteristic of Reverse Diode

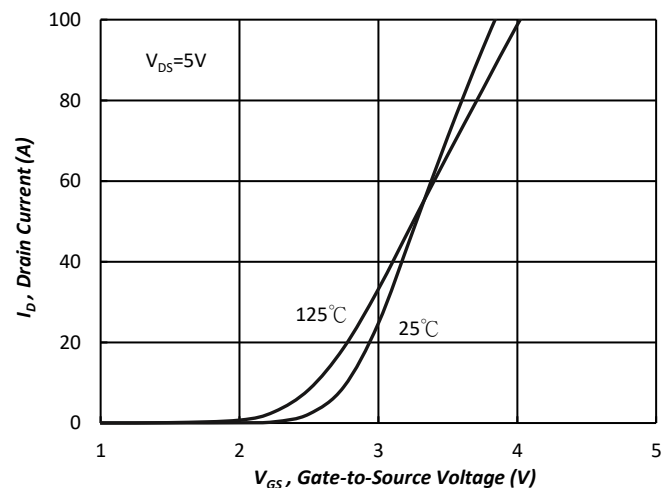


Fig.6 Transfer Characteristics

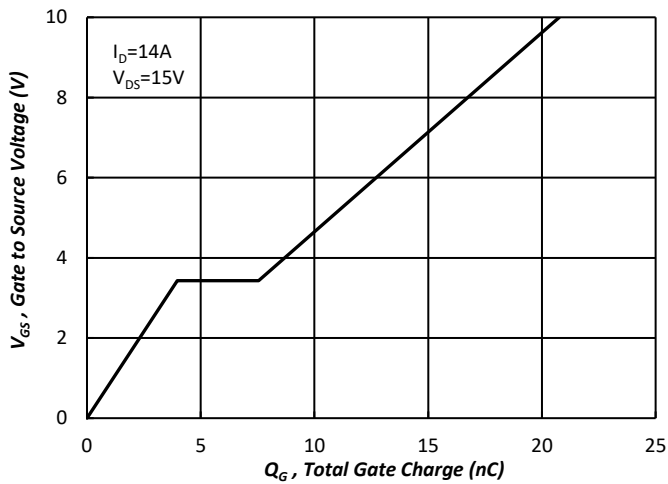


Fig.7 Gate Charge Characteristics

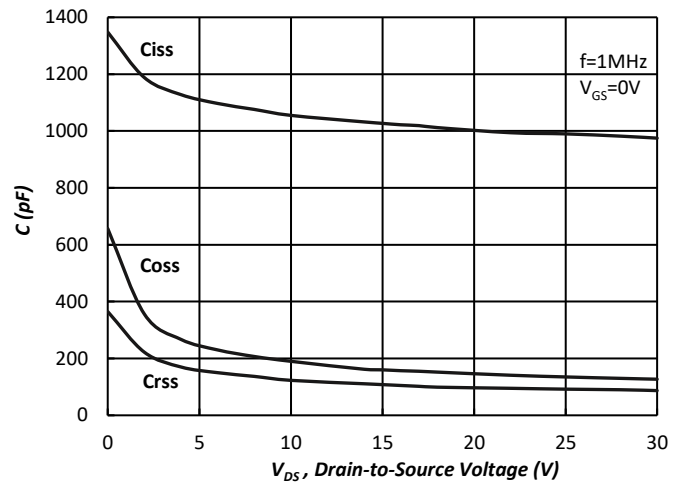


Fig.8 Typical Capacitance Characteristics

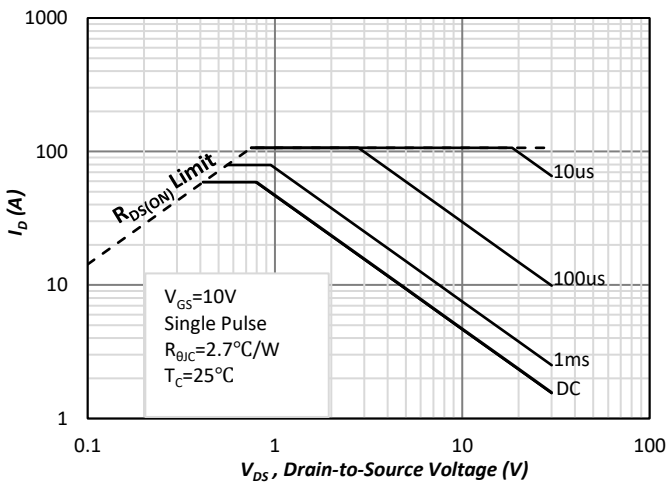


Fig.9. Maximum Safe Operating Area

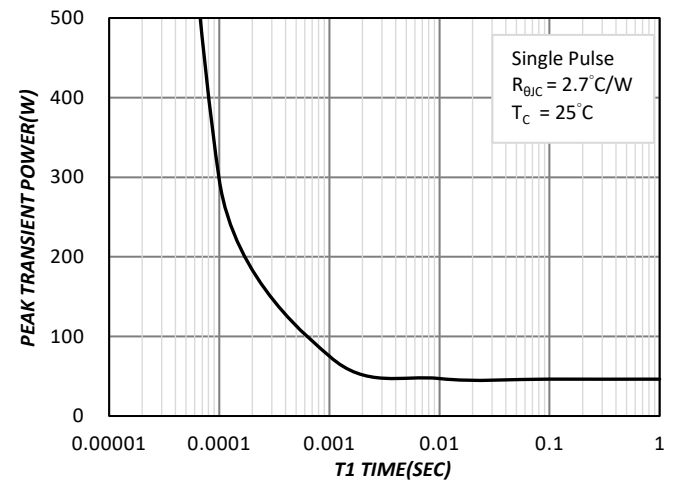


Fig.10. Single Pulse Maximum Power Dissipation

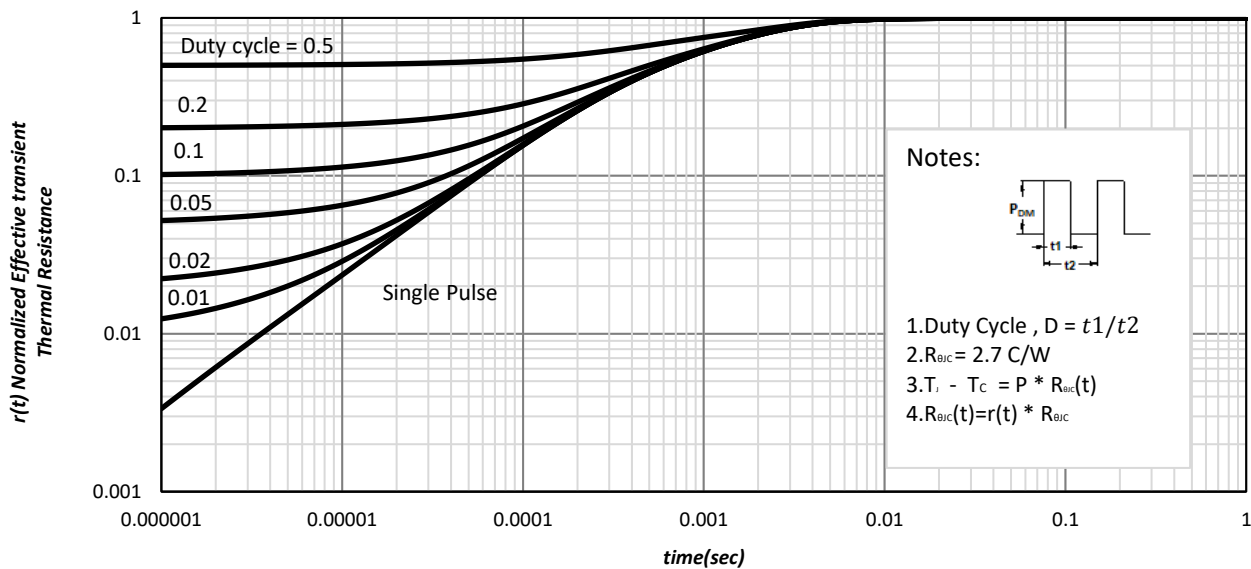


Fig.11. Effective Transient Thermal Impedance

Ordering & Marking Information:

Device Name: EMB07N03V for EDFN 3x3



B07N03: Device Name

ABCDEFGH: Date Code

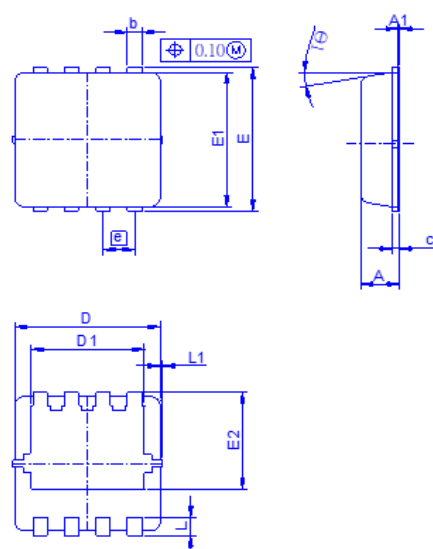
A: Assembly House

B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

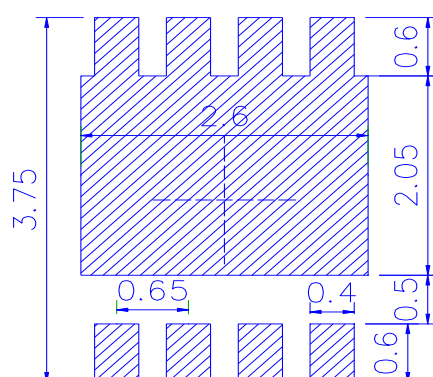
DEFG: Serial No.

Outline Drawing

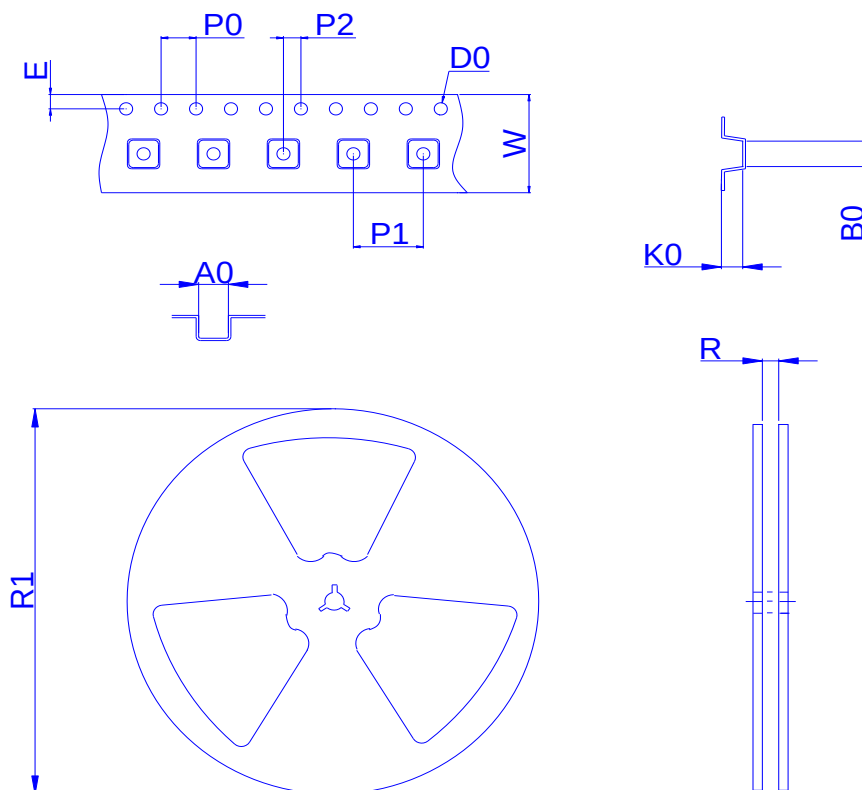


Dimension	A	A1	b	c	D	D1	E	E1	E2	e	L	L1	Θ1
Min.	0.65	0	0.20	0.10	2.90	2.15	3.10	2.90	1.53	0.55	0.25	-	0°
Typ.	0.75	-	0.30	0.15	3.00	2.45	3.20	3.00	1.97	0.65	0.40	0.075	10°
Max.	0.90	0.05	0.40	0.25	3.30	2.74	3.50	3.30	2.59	0.75	0.60	0.15	14°

Footprint



◆ Tape&Reel Information:5000pcs/Reel



Package	EDFN3X3
Reel	13"
Device orientation	FEED DIRECTION

Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	3.6	3.6	1.55	1.7	1.2	4	8	2	12	12.4	330
±	0.3	0.3	0.2	0.2	0.2	0.1	0.1	0.1	1	2	2